

11/20/03

10/718400

INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)				ATTY DOCKET NO. 14846-36	SERIAL NO. TBA		
				Methods and Systems For Predicting Software Defects.....			
FILING November 20, 2003				GROUP	TBA		
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SGN		US 6,073,107	06/06/00	Minkiewicz et al.			
SGN		US 6,477,471	11/05/02	Hedstrom et al.			
SGN		US 6,546,506	04/08/03	Lewis			
SGN		US 5,446,895	08/29/95	White et al.			
SGN		US 5,655,074	08/05/97	Rauscher			
SGN		US 5,758,061	05/26/98	Plum			
SGN		US 5,903,897	05/11/99	Carrier III et al.			
SGN		US 5,960,196	09/28/99	Carrier III et al.			
SGN		US 6,363,524	03/26/02	Loy			
SGN		US 6,405,364	06/11/02	Bowman-Amuah			
SGN		US 6,513,154	01/28/03	Porterfield			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES
							NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
SGN		Hudepohl, J.P., et al., "Integrating Metrics and Models For Software Risk Assessment," p. 93, The Seventh International Symposium on Software Reliability Engineering (ISSRE'96) October 30-November 02, 1996, White Plains, NY (Abstract)					
SGN		Levendel, Y., "Reliability Analysis of Large Software Systems: Defect Data Modeling," pp. 141-152, IEEE Transactions on Software Engineering (Abstract)					
EXAMINER /Samuel Neway/				DATE CONSIDERED 07/21/2006			
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SGN		US 6,519,763	02/11/03	Kaufer et al.			
SGN		US 6,601,017	07/29/03	Kennedy et al.			
SGN		US 6,601,018	07/29/03	Logan			
SGN		US 6,601,233	07/29/03	Underwood			
SGN		US 6,626,953	09/30/03	Johndrew et al.			
SGN		US 6,629,266	09/30/03	Harper et al.			
SGN		US 2002/0147961	10/10/02	Charters et al.			
SGN		US 2002/0162090	10/31/02	Parnell et al.			
SGN		US 2003/0018952	01/23/03	Roetzheim			
SGN		US 2003/0033586	02/13/03	Lawler			
SGN		US 2003/0188290	10/02/03	Corral			
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							YES
							NO
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SGN		Yu, T.J., et al., "An Analysis of Several Software Defect Models," pp. 1261-1270, IEEE Transactions on Software Engineering (Abstract)					
SGN		Wohlin, C., et al., "Understanding the Sources of Software Defects: A Filtering Approach, 8th International Workshop on Program Comprehension (IWPC'00), June 10-11, 2000 (Abstract)					
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SGN		US 2003/0196190	10/16/03	Ruffolo et al.				
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							YES	NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)								
SGN			McConnell, S., "Gauging Software Readiness with Defect Tracking," IEEE Software, pp. 135-136 (Abstract)					
SGN			Mohapatra, S., et al., "Defect Prevention through Defect Prediction: A Case Study at Infosys," Utkal University, IEEE International Conference on Softwars Maintenance (ICSM'01), November 7-9, 2001, p. 260 (Abstract)					
EXAMINER <i>/Samuel Neway/</i>				DATE CONSIDERED <i>07/21/2006</i>				

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SGN			Basili, V., et al., "Understanding and Predicting the Process of Software Maintenance Releases," 18th International Conference on Software Engineering (ICSE'96), arch 25-29, 1996, p. 464 (Abstract)				
SGN			Fenton, N.E., et al., "A Critique of Software Defect Prediction Models," IEEE Transactions on Software Engineering; pp. 675-689 (Abstract)				
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